

IN THE SPECIFICATION

Please amend Paragraph [0067], Pages 23-24, of the specification as follows:

[0067] Then the measured thickness of the layer of thermal oxide 810 is correlated in real time to a germanium concentration of the silicon germanium film 710 using an approximately linear correlation (step 1350). In this manner a value of the germanium concentration in the silicon germanium film 710 is obtained in real time (step 1370). Then the manufacture of the silicon germanium film 710 is controlled in real time using the value of the germanium concentration (step 1370).